

<b>Notice of References Cited</b>	Application/Control No. 10/643,520	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Caridad M. Everhart	Art Unit 2825	Page 1 of 1

U.S. PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,405,801	04-1995	Han et al.	438/386
	B	US-2002/0064956	05-2002	Wu et al.	438/692
	C	US-5,786,250	07-1998	Wu et al.	438/254
	D	US-2003/0102469	06-2003	Jones et al.	257/9
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2002222871	08-2002	Japan	Kato, et al.	H01L 21/8242
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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